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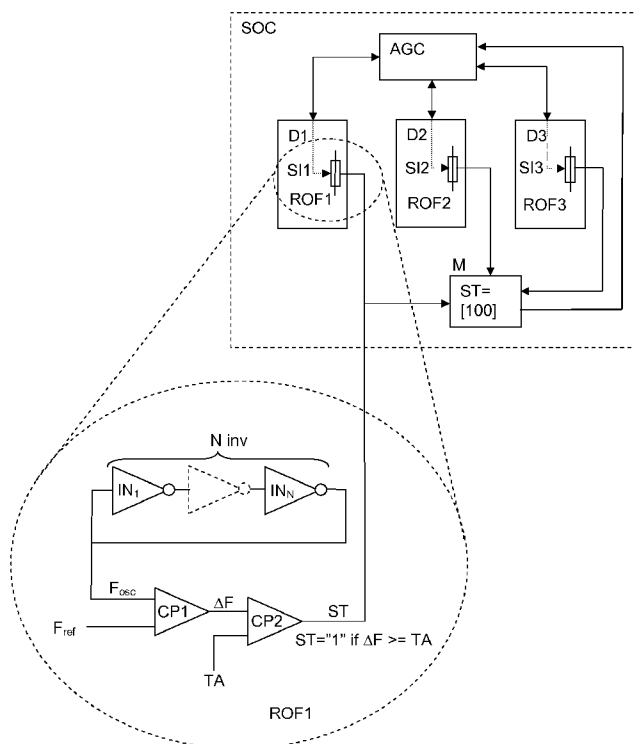
(54) **Title:** AGING CONTROL OF A SYSTEM ON CHIP

Fig. 1

(57) **Abstract:** A method to control aging of a system on chip comprising one or more devices including semiconductor circuit components and at least one aging controller monitoring electrical signals circulating inside the system on chip. The method comprises steps of stressing at least one device of the system on chip by varying hardware parameters related to its operating mode, comparing at least one parameter associated with an electrical signal produced by the at least one device with a reference parameter to determine a difference corresponding to an operating age value of the at least one device, if the operating age value equals or exceeds a threshold age value, determining a stress state value and modifying the operating mode of the at least one device according to the stress state value. A system on chip performing the method is also disclosed.

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